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Lee, D.; Netravali, A.N.; Sabnani, K.K.;
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Dahbura, A.T.; Sabnani, K.K.; Uyar, M.U.;
 Proceedings of the IEEE, Volume: 78, Issue: 8, Aug. 1990
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Pendse, N.; Thomas, D.; Das, D.; Pecht, M.G.;
 Components and Packaging Technologies, IEEE Transactions on [see also Components, Packaging and Manufacturing Technology, Part A: Packaging Technologies, IEEE Transactions on], Volume: 25, Issue: 2, June 2002
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Das, D.; Pendse, N.; Wilkinson, C.; Pecht, M.G.;
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5 Effect of local stir and spatial averaging on measurement and testing in m de-tuned and m de-stirred reverberation chambers*Arnaut, L.R.;*

Electromagnetic Compatibility, IEEE Transactions on, Volume: 43, Issue: 3, Aug. 2001

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[\[Abstract\]](#) [\[PDF Full-Text \(724 KB\)\]](#) [IEEE JNL](#)**6 Reliability of conformance tests***Hagwood, C.; Rosenthal, L.;*

Reliability, IEEE Transactions on, Volume: 50, Issue: 2, June 2001

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Engineering Management, IEEE Transactions on, Volume: 48, Issue: 4, Nov.

2001

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Computer Graphics and Applications, IEEE, Volume: 19, Issue: 2, March-April

1999

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[\[Abstract\]](#) [\[PDF Full-Text \(376 KB\)\]](#) [IEEE JNL](#)**10 Scientific foundations to the multilevel method***Neelakantan, B.; Raghavan, S.V.;*

Networking, IEEE/ACM Transactions on, Volume: 6, Issue: 3, June 1998

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agents using SDL-92

Henniger, O.; Barbeau, M.; Sarikaya, B.;
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Fendick, K.W.;
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14 Conformance testing of protocols specified as communicating finite state machines-a guided random walk based approach

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15 Synchronizable test sequences based on multiple UIO sequences

Wen-Huei Chen; Hasan Urai;
Networking, IEEE/ACM Transactions on, Volume: 3, Issue: 2, April 1995
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Very Large Scale Integration (VLSI) Systems, IEEE Transactions on, Volume: 3, Issue: 2, June 1995
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Gopalakrishnan, G.; Brunvand, E.; Michell, N.; Nowick, S.M.;
Computer-Aided Design of Integrated Circuits and Systems, IEEE Transactions on, Volume: 13, Issue: 11, Nov. 1994
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[\[Abstract\]](#) [\[PDF Full-Text \(880 KB\)\]](#) **IEEE JNL****18 A revised conformance test method of layer 3 of HBS standard**

Hamabe, R.; Murata, M.; Honda, Y.; Yamamoto, T.; Kumagai, A.;
Consumer Electronics, IEEE Transactions on, Volume: 40, Issue: 3, Aug 1994
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Gang Luo; von Bochmann, G.; Petrenko, A.;
Software Engineering, IEEE Transactions on, Volume: 20, Issue: 2, Feb. 1994
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Baumert, J.H.;
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Zelkowitz, M.V.; Buckley, F.J.;
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Shen, Y.-N.; Lombardi, F.; Dahbura, A.T.;
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Lombardi, F.; Shen, Y.-N.;
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Naik, K.; Sarikaya, B.;
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Fujiwara, S.; v. Bochmann, G.; Khendek, F.; Amalou, M.; Ghedamsi, A.;

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30 A test sequence selection method for protocol testing

Ural, H.; Yang, B.;

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